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				Filing Date		February 24, 2004	
				First Named Inventor:		Chee-Wee Liu	
				Examiner name: unknown		GROUP: unknown	
Sheet	1	of	1	Attorney Docket Number		D&F-040	

U.S. PATENT DOCUMENTS

Examiner Initials*	Cited No. ¹	Document Number Number - Kind Code ^{2(f/known)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages or Figures Appear
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document Cntry Code ³ Number ⁴ Kind Code ^{5 (f/known)}	Publication Date MM-DD- YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages or Figures Appear	T ⁶

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	G. Kastner and Gosele, "Principles Of Strain Relaxation In Heteroepitaxial Films Growing On Compliant Substrate", J. Appl. Phys., Vol. 88, pp. 4048-4055, 2000.
	F. M. Bufler et al., "Hole and Electron Transport In Strained Si: Orthorhombic Versus Biaxial Tensile Strain", Appl. Phys. Lett., Vol. 81, pp. 82-84, 2002.
	F. M. Bufler, "Hole Transport In Orthorhombically Strained Si", Journal Of Computational Electronics, Vol. 1, pp. 175-177, 2002.
	Xin Wang et al., "Monte Carlo Simulation Of Electron Transport In Simple Orthorhombically Strained Silicon", J. Appl. Phys., Vol. 88, pp. 4717-4724, 2000.
	M. V. Fischetti, F. Gamiz, and W. Hansch, "On The Enhanced Electron Mobility In Strained-Silicon Inversion Layers", Journal of Applied Physics, Vol. 92, pp. 7320-7324, 2002.

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